

**FCC ID: 2BEBP-LK56**

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission’s guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$  for 1-g SAR and  $\leq 7.5$  for 10-g extremity SAR, where:

- f(GHz) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	1.74	1.49	1.5±1	2.5	1.78	<5	0.55121	3.00	YES
	2.441	0.72	1.18	1.5±1	2.5	1.78	<5	0.55567	3.00	YES
	2.480	1.44	1.39	1.5±1	2.5	1.78	<5	0.56009	3.00	YES
π/4-DQPSK	2.402	2.63	1.83	2±1	3	2.00	<5	0.61847	3.00	YES
	2.441	1.53	1.42	2±1	3	2.00	<5	0.62347	3.00	YES
	2.480	2.24	1.67	2±1	3	2.00	<5	0.62843	3.00	YES
BLE(1M)	2.402	-0.56	0.88	0.5±1	1.5	1.41	<5	0.43784	3.00	YES
	2.440	0.67	1.17	1±1	2	1.58	<5	0.49514	3.00	YES
	2.480	1.36	1.37	1±1	2	1.58	<5	0.49918	3.00	YES
BLE(2M)	2.402	-0.45	0.90	0.5±1	1.5	1.41	<5	0.43784	3.00	YES
	2.440	0.75	1.19	1±1	2	1.58	<5	0.49514	3.00	YES
	2.480	1.52	1.42	1±1	2	1.58	<5	0.49918	3.00	YES

**Conclusion:**

For the max result : 0.62843 ≤ 3.0 for 1g SAR, SAR is not required.

**Signature:**

**Date:** 2024-07-09

**NAME AND TITLE** (Please print or type): Alex li /Manager

**COMPANY** (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen P.R. China.